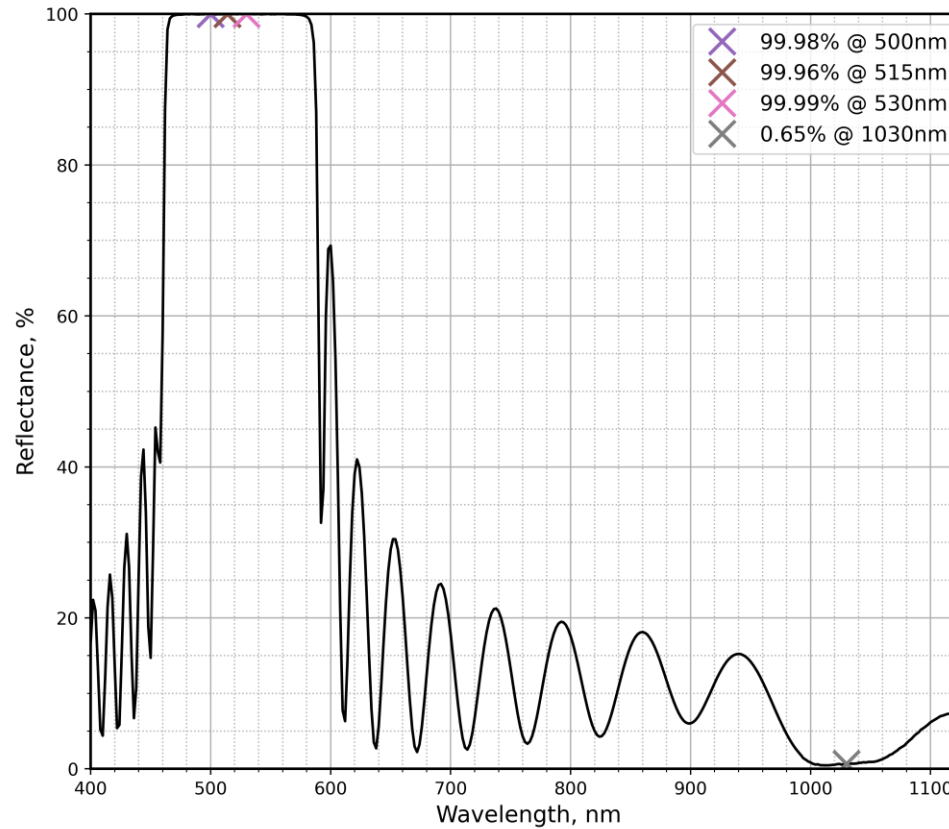


S1: (arrow marks) HRsp>99.9% @ 515 nm + HRsp>99.3% @ 500- 530 nm + Rsp<2% @ 1030 nm, AOI=45 deg, GDD\_R <20 fs<sup>2</sup>  
 S2: ARsp<0.6% @ 1030 nm, AOI=45 deg



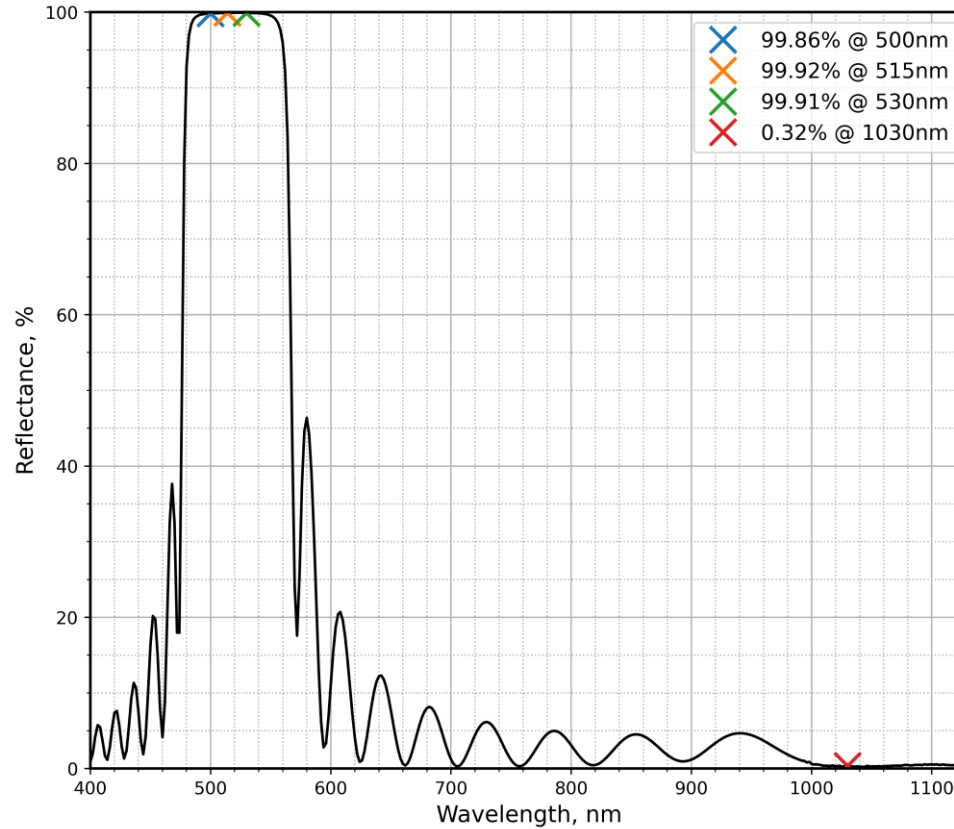
PO4612 Rs i45

Fig. 1.

SIDE MEASURED: S1 only (grinded witness sample)

COMMENTS: Margin of measurement error: +/-0.25%

S1: (arrow marks) HRsp>99.9% @ 515 nm + HRsp>99.3% @ 500- 530 nm + Rsp<2% @ 1030 nm, AOI=45 deg, GDD\_R <20 fs<sup>2</sup>  
 S2: ARsp<0.6% @ 1030 nm, AOI=45 deg



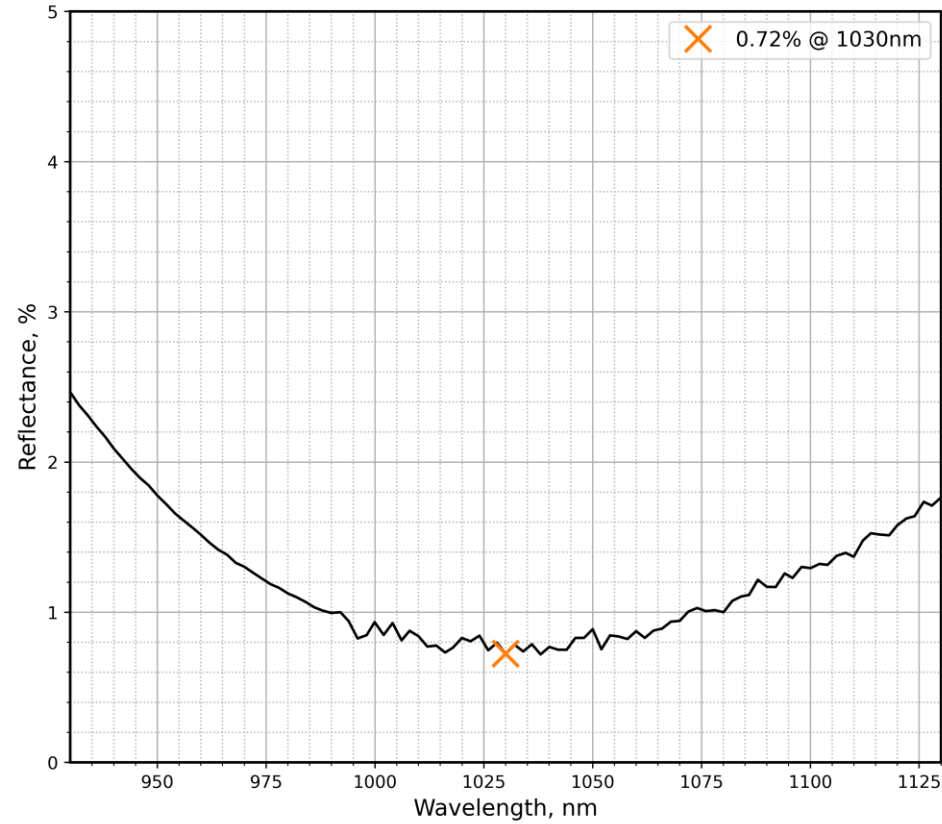
PO4612 Rp i45

Fig. 2.

SIDE MEASURED: S1 only (grinded witness sample)

COMMENTS: Margin of measurement error: +/-0.25%

S1: (arrow marks) HRsp>99.9% @ 515 nm + HRsp>99.3% @ 500- 530 nm + Rsp<2% @ 1030 nm, AOI=45 deg, GDD\_R <20 fs<sup>2</sup>  
S2: ARsp<0.6% @ 1030 nm, AOI=45 deg



PO4612 Rs i45

Fig. 3.

SIDE MEASURED: S2 only (grinded witness sample)

COMMENTS: Margin of measurement error: +/-0.25%

S1: (arrow marks) HRsp>99.9% @ 515 nm + HRsp>99.3% @ 500- 530 nm + Rsp<2% @ 1030 nm, AOI=45 deg, GDD\_R <20 fs<sup>2</sup>  
S2: ARsp<0.6% @ 1030 nm, AOI=45 deg

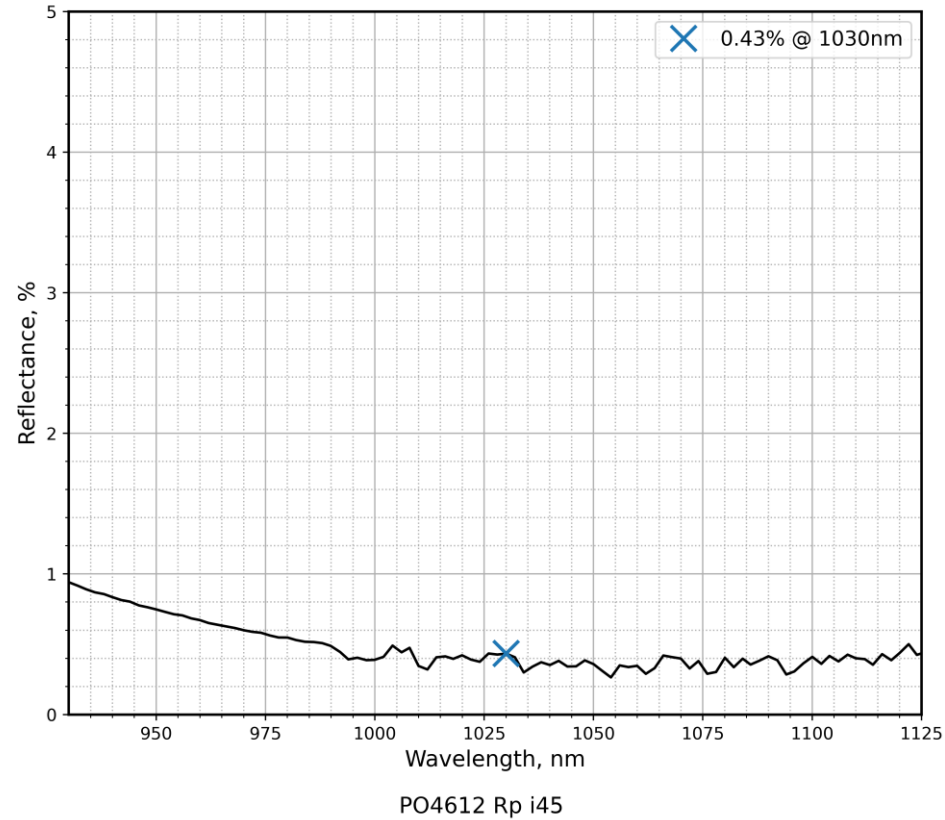


Fig. 4.

SIDE MEASURED: S2 only (grinded witness sample)

COMMENTS: Margin of measurement error: +/-0.25%